

L Number	Hits	Search Text	DB	Time stamp
1	0	09/856982	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/16 15:48
2	7	"6292259"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/16 16:03
3	8540	inspect\$3 near9 wafer	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/16 16:05
4	6	(inspect\$3 near9 wafer) and multiple near1 optics	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/16 16:07
5	0	(inspect\$3 near9 wafer) and multiple near light near optics	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/16 16:08
6	587	(inspect\$3 near9 wafer) and occurrence	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/16 16:21
7	94	((inspect\$3 near9 wafer) and occurrence) and scattered and reflected	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/16 16:09
8	0	((((inspect\$3 near9 wafer) and occurrence) and scattered and reflected) and ratio near6 (light near optics)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/16 16:10
9	63	((((inspect\$3 near9 wafer) and occurrence) and scattered and reflected) and ratio and determin\$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/16 16:10
12	2	(((((inspect\$3 near9 wafer) and occurrence) and scattered and reflected) and ratio and determin\$4) and 356/237.3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/16 16:10
13	5	(((((inspect\$3 near9 wafer) and occurrence) and scattered and reflected) and ratio and determin\$4) and 356/237.4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/16 16:10
15	0	(((((inspect\$3 near9 wafer) and occurrence) and scattered and reflected) and ratio and determin\$4) and 356/237.6	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/16 16:10
17	3	(((((inspect\$3 near9 wafer) and occurrence) and scattered and reflected) and ratio and determin\$4) and 382/\$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/16 16:11
10	6	(((((inspect\$3 near9 wafer) and occurrence) and scattered and reflected) and ratio and determin\$4) and 356/237.1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/16 16:12

11	7	(((((inspect\$3 near9 wafer) and occurrence) and scattered and reflected) and ratio and determin\$4) and 356/237.2	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/05/16 16:13
14	8	(((((inspect\$3 near9 wafer) and occurrence) and scattered and reflected) and ratio and determin\$4) and 356/237.5	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/05/16 16:14
16	38	(((((inspect\$3 near9 wafer) and occurrence) and scattered and reflected) and ratio and determin\$4) and 250/\$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/05/16 16:21
18	151	(inspect\$3 near9 wafer) and occurrence near2 defect	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/05/16 16:21
19	36	((inspect\$3 near9 wafer) and occurrence near2 defect) and 356/\$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/05/16 16:22

L	Number	Hits	Search Text	DB	Time stamp
2		1883	ratio near2 (light near intensities)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/16 16:59
3		7906	inspection and scanner	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/16 17:11
1		12	multiple near light near optics	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/16 17:00
4		19	(ratio near2 (light near intensities)) and (inspection and scanner)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/16 17:03
5		8	(ratio near2 (light near intensities)) and 356/237.1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/16 17:05
6		101	(inspection and scanner) and 356/237.1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/16 17:08
7		88	(inspection and scanner) and 356/237.5	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/16 17:08
8		10	inspect\$3 near2 defect and (ratio near2 (light near intensities))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/16 17:13
9		50	(inspect\$3 near3 wafer) and (detect\$3 near6 (scatter\$3 and reflect\$3))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/05/16 17:15
10		1		USPAT	2003/05/16 17:19